AMENDMENTS TO THE CLAIMS

1. (Currently Amended) A contact pin for contacting a terminal of an electronic device to supply the electronic device with a signal, the contact pin comprising:

a first conductive layer composed of a first conductive material ; and

a second conductive layer composed of a second conductive material with a lower hardness than the first conductive material,

wherein the first conductive layer is formed at the outside from the second conductive ~~layer.~~layer,

the contact pin has a truncated cone shape which has a first flat surface at the front end and a first taper portion which tapers toward the first flat surface,

the first flat surface is orthogonal to the axis of the contact pin, and

the second conductive layer is exposed at the first flat surface.

2. (Previously Presented) The contact pin as set forth in claim 1, wherein the first conductive material has a hardness higher than an oxide film formed on the terminal of the electronic device; and

the second conductive material has a lower hardness than the oxide film formed on the terminal of the electronic device.

3. (Currently Amended) The contact pin as set forth in claim 1, wherein

the contact pin has a circular cylindrical shape with the truncated cone shape.

~~the contact pin has a taper portion which tapers toward the front end face of the contact pin, and~~

~~the front end face of the contact pin is flat.~~

4. (Currently Amended) The contact pin as set forth in claim 1, wherein

the contact pin further comprises a base material at the outside of which the first conductive layer and the second conductive layer are formed, wherein

the base material has a second flat surface at the front end and a second taper portion which tapers toward the second flat surface,

the second flat surface is orthogonal to the axis of the contact pin, and

the second conductive layer covers the second flat surface.

~~both the first conductive layer and the second conductive layer are exposed at the front end face of the contact pin; and the base material is arranged inside the contact pin such that the front end of that base material is separated by a predetermined distance from the front end of the contact pin.~~

5. (Canceled)

6. (Previously Presented) The contact pin as set forth in claim 1, wherein the first conductive layer is formed so as to be in close contact with the outside of the second conductive layer.

7. (Currently Amended) The contact pin as set forth in claim 1, wherein

the first conductive layer circularly surrounds the second conductive layer in the first flat surface, and ~~front end of the contact pin, and~~

the front end of the first conductive layer and the second conductive layer are in the same plane. ~~layers form the front end face of the contact pin.~~

8. (Canceled)

9. (Withdrawn) The contact pin as set forth in claim 1, wherein a plurality of at least of said first conductive layer or said second conductive layer is provided.

10. (Presently Presented) A probe card having contact pins of claim 1 electrically connected to a test head of an electronic device test apparatus and a board upon one main surface of which the contact pins are provided, the contact pins being brought into contact with terminals of an electronic device to test the electronic device.

11. (Currently Amended) The probe card as set forth in claim 10, wherein

the first conductive material has a hardness higher than ~~the~~ an oxide film formed on the terminal of the electronic device, and

the second conductive material has a lower hardness than the oxide film formed on the terminal of the electronic device.

12. (Currently Amended) The probe card as set forth in claim 10, wherein

the contact pin has a circular cylindrical shape with the truncated cone shape.

~~the contact pin has a taper portion which tapers toward the front end face of the contact pin, and~~

~~the front end face of the contact pin is flat.~~

13. (Currently Amended) The probe card as set forth in claim 10, wherein

the contact pin further comprises a base material at the outside of which the first conductive layer and the second conductive layer are formed, wherein

the base material has a second flat surface at the front end and a second taper portion which tapers toward the second flat surface,

the second flat surface is orthogonal to the axis of the contact pin, and

the second conductive layer covers the second flat surface.

~~both the first conductive layer and the second conductive layer are exposed at the front end face of the contact pin the base material is arranged inside the contact pin such that the front end of that base material is separated by a predetermined distance from the front end of the contact pin.~~

14. (Canceled)

15. (Previously Presented) The probe card as set forth in claim 10, wherein the first conductive layer is formed so as to be in close contact with the outside of the second conductive layer.

16. (Currently Amended) The probe card as set forth in claim 10, wherein

the first conductive layer circularly surrounds the second conductive layer in the first flat surface, and ~~in the front end of the contact pin, and~~

the front end of the first conductive layer and the second conductive layer are in the same plane. ~~layers form the front end face of the contact pin.~~

17. (Canceled)

18. (Withdrawn) The probe card as set forth in claim 10, wherein a plurality of at least of said first conductive layer or said second conductive layer is provided.

19. (Original) An electronic device test apparatus having a test head to which a probe card of claim 10 is electrically connected.

20. (Currently Amended) The electronic device test apparatus as set forth in claim 19, wherein

the first conductive material has a hardness higher than ~~the~~ an oxide film formed on the terminal of the electronic device, and

the second conductive material has a lower hardness than the oxide film formed on the terminal of the electronic device.

21. (Currently Amended) The electronic device test apparatus as set forth in claim 19, wherein

the contact pin has circular cylindrical shape with the truncated cone shape. ~~the contact pin has a taper portion which tapers toward the front end face of the contact pin, and~~

~~the front end face of the contact pin is flat.~~

22. (Currently Amended) The electronic device test apparatus as set forth in claim 19, wherein

the contact pin further comprises a base material at the outside of which the first conductive layer and the second conductive layer are formed, wherein

the base material has a second flat surface at the front end and a second taper portion which tapers toward the second flat surface,

the second flat surface is orthogonal to the axis of the contact pin, and

the second conductive layer covers the second flat surface.

~~both the first conductive layer and the second conductive layer are exposed at the front end face of the contact pin~~

~~the base material is arranged inside the contact pin such that the front end of that base material is separated by a predetermined distance from the front end of the contact pin.~~

23. (Canceled)

24. (Previously Presented) The electronic device test apparatus as set forth in claim 19, wherein the first conductive layer is formed so as to be in close contact with the outside of the second conductive layer.

25. (Currently Amended) The electronic device test apparatus as set forth in claim 19, wherein

the first conductive layer circularly surrounds the second conductive layer in the first flat surface, and ~~in the front end of the contact pin, and~~

the front end of the first conductive layer and the front end of the second conductive layer are in the same plane. ~~layers form the front end face of the contact pin.~~

26. (Canceled)

27. (Withdrawn) The electronic device test apparatus as set forth in claim 19, wherein a plurality of at least of said first conductive layer or said second conductive layer is provided.